


<b>Search Notes</b>  	<b>Application/Control No.</b>  10552709	<b>Applicant(s)/Patent Under Reexamination</b>  HATAKEYAMA ET AL.
	<b>Examiner</b>  HENG M CHAN	<b>Art Unit</b>  4181

SEARCHED			
Class	Subclass	Date	Examiner
423	445B, 500, DIG39, DIG40	2/18/2009	HMC
427	487,488,533,569,903	2/18/2009	HMC
428	832.4, 835, 835.1	2/18/2009	HMC
422	186, 186.04	2/18/2009	HMC
977	734, 740, 843, 844, 847	2/18/2009	HMC

SEARCH NOTES		
Search Notes	Date	Examiner
EAST databases:USPAT, US-PGPUB, USOCR, EPO, JPO, DERWENT, IBM-TDB, FPRS	2/18/2009	HMC
Inventors searched in Palm	2/17/2009	HMC
Google search for background knowlege about fullerenes	2/18/2009	HMC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/HENG M CHAN/ Examiner, Art Unit 4181	
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